

**Notice of References Cited**

Application/Control No.

10/568,479

Applicant(s)/Patent Under  
Reexamination  
ECK ET AL.

Examiner

JON CHANG

Art Unit

2624

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,285,786	02-1994	Fujii, Senzo	600/425
*	B	US-6,859,548	02-2005	Yoshioka et al.	382/128
*	C	US-2004/0081269	04-2004	Pan et al.	378/004
*	D	US-5,797,843	08-1998	Fitch et al.	600/437
*	E	US-6,370,417	04-2002	Horbaschek et al.	600/424
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.